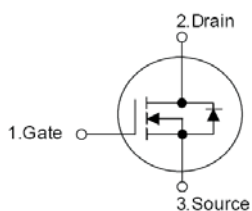
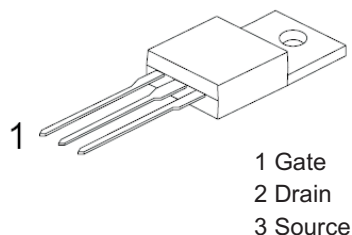


■ Features

- $R_{DS(ON)} = 3.8 \Omega @ V_{GS} = 10V$ .
- Low gate charge ( typical 9.0 nC).
- Low  $C_{rss}$  ( typical 5.0 pF).
- Fast switching capability.
- Avalanche energy specified
- Improved  $dv/dt$  capability.

TO-220



■ Absolute Maximum Ratings  $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DSS}$	600	V
Gate-Source Voltage	$V_{GSS}$	$\pm 30$	V
Drain Current - Continuous ( $T_c = 25^\circ C$ ) Continuous ( $T_c = 100^\circ C$ )	$I_D$	2.0 1.26	A
Drain Current - Pulsed * 1	$I_{DP}$	8.0	A
Single Pulsed Avalanche Energy * 2	$E_{AS}$	140	mJ
Avalanche Current * 1	$I_{AR}$	2.0	A
Repetitive Avalanche Energy * 1	$E_{AR}$	4.5	mJ
Peak Diode Recovery $dv/dt$ * 3	$dv/dt$	4.5	V/ns
Power Dissipation ( $T_c = 25^\circ C$ ) Derate above $25^\circ C$	$P_D$	44 0.36	W W/ $^\circ C$
Operating and Storage Temperature Range	$T_J, T_{stg}$	-55 to +150	$^\circ C$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	$T_L$	300	$^\circ C$
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	4	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	54	$^\circ C/W$

\* 1. Repetitive Rating : Pulse width limited by maximum junction temperature.

\* 2.  $L = 64mH, I_{AS} = 2.0A, V_{DD} = 50V, R_G = 25 \Omega, \text{ Starting } T_J = 25^\circ C$

\* 3.  $I_{SD} \leq 2.4A, di/dt \leq 200A/\mu s, V_{DD} \leq BV_{DSS}, \text{ Starting } T_J = 25^\circ C$

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test conditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	600			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V			10	μA
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C			100	μA
Gate-Body Leakage Current, Forward	I <sub>GSSF</sub>	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
Gate-Body Leakage Current, Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0		4.0	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1 A		3.8	5.0	Ω
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> = 50V, I <sub>D</sub> = 1 A * 1		2.25		S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		270	350	pF
Output Capacitance	C <sub>oss</sub>			40	50	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			5	7	pF
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 300 V, I <sub>D</sub> = 2.4 A, R <sub>G</sub> = 25 Ω *1,2		10	30	ns
Turn-On Rise Time	t <sub>r</sub>			25	60	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			20	50	ns
Turn-Off Fall Time	t <sub>f</sub>			25	60	ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 2.4A, V <sub>GS</sub> = 10 V *1,2		9	11	nC
Gate-Source Charge	Q <sub>gs</sub>			1.6		nC
Gate-Drain Charge	Q <sub>gd</sub>			4.3		nC
Maximum Continuous Drain-Source Diode Forward Current	I <sub>S</sub>				2	A
Maximum Pulsed Drain-Source Diode Forward Current	I <sub>SM</sub>				8	A
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.0 A			1.4	V
Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.4 A,		180		ns
Reverse Recovery Charge	Q <sub>rr</sub>	dI <sub>F</sub> / dt = 100 A/μs * 1		0.72		μC

\* 1. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%

\* 2. Essentially independent of operating temperature.